## Notice of References Cited Application/Control No. 10/573,221 Examiner AKLILU k. WOLDEMARIAM Applicant(s)/Patent Under Reexamination SIMON ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	А	US-5,201,047 A	04-1993	Maki et al.	707/4
*	В	US-5,612,928 A	03-1997	Haley et al.	367/11
*	С	US-5,640,464 A	06-1997	Ebel et al.	382/143
*	D	US-5,675,710 A	10-1997	Lewis, David Dolan	706/12
*	Е	US-6,192,360 B1	02-2001	Dumais et al.	707/6
*	F	US-2002/0012467 A1	01-2002	Shiratani, Fumiyuki	382/224
*	G	US-2003/0005030 A1	01-2003	Sutton et al.	709/200
*	Н	US-6,622,134 B1	09-2003	Sorkin, Gregory Bret	706/20
*	I	US-2004/0062435 A1	04-2004	Yamaoka et al.	382/159
*	J	US-2004/0213439 A1	10-2004	Blake et al.	382/118
*	К	US-2005/0122118 A1	06-2005	Zank et al.	324/457
*	L	US-6,976,207 B1	12-2005	Rujan et al.	715/234
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.